

**In the Abstract:**

Insert a new abstract as follows:

Connection circuitry provides for TAP and internal scan test ports to be merged so they both can co-exist and operate from the same set of IC pins and/or core leads or terminals. This arrangement provides for the merged TAP and scan test port interfaces to be selected individually or in groups. Internal Tap Lock circuitry uses only the existing 1149.1 interface signals to produce a Lock Out signal to enable and disable a TMS/CS signal to the TAP circuitry.